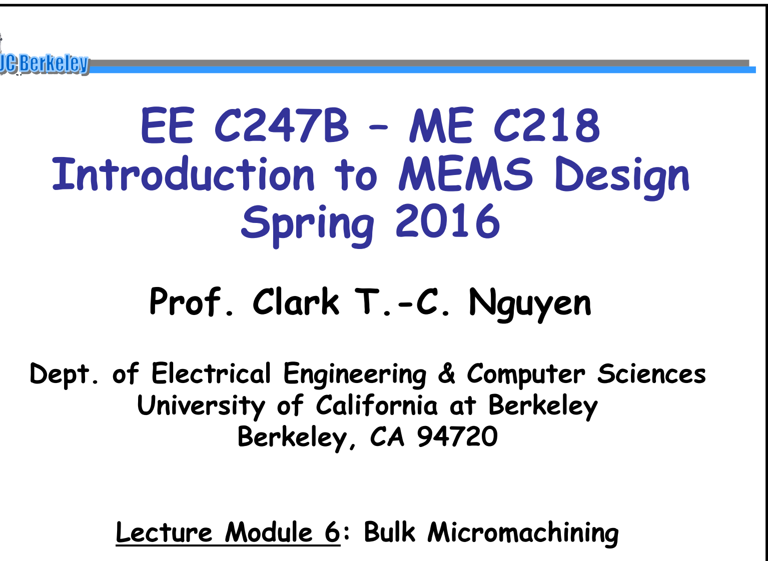
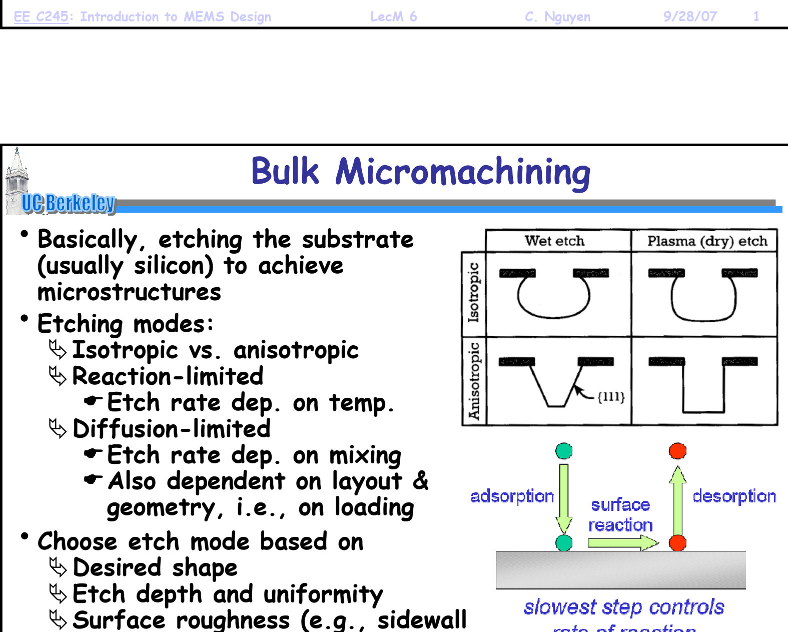
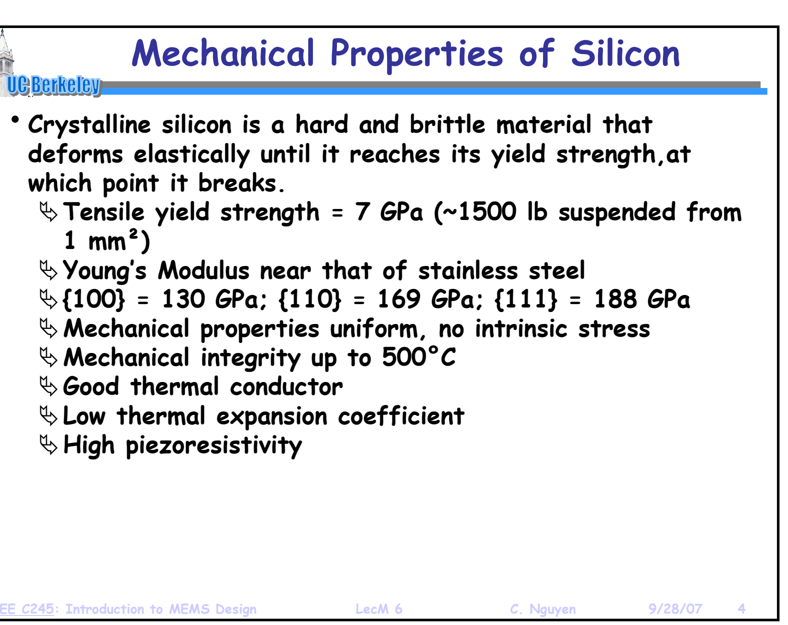


Lecture Outline

- Reading: Senturia Chpt. 3, Jaeger Chpt. 11, Handouts: "Bulk Micromachining of Silicon"
- Lecture Topics:
  - Bulk Micromachining
  - Anisotropic Etching of Silicon
  - Boron-Doped Etch Stop
  - Electrochemical Etch Stop
  - Isotropic Etching of Silicon
  - Deep Reactive Ion Etching (DRIE)





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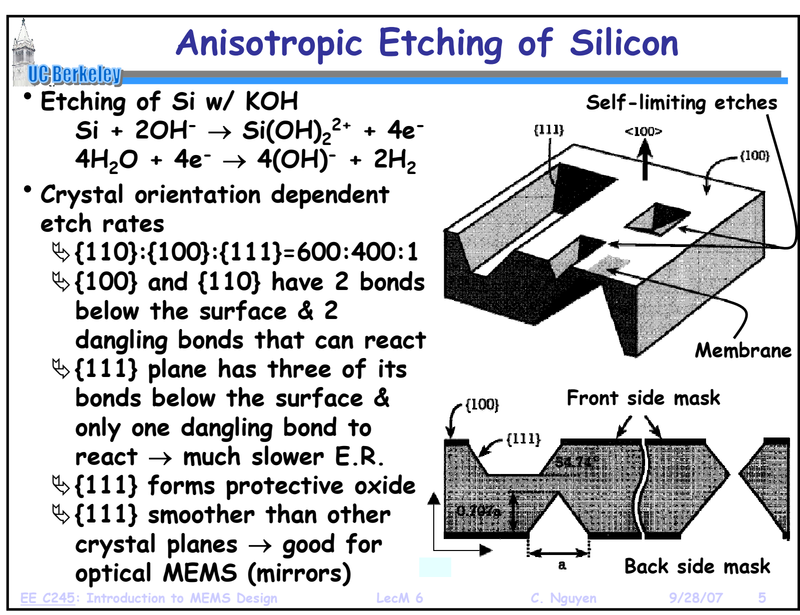

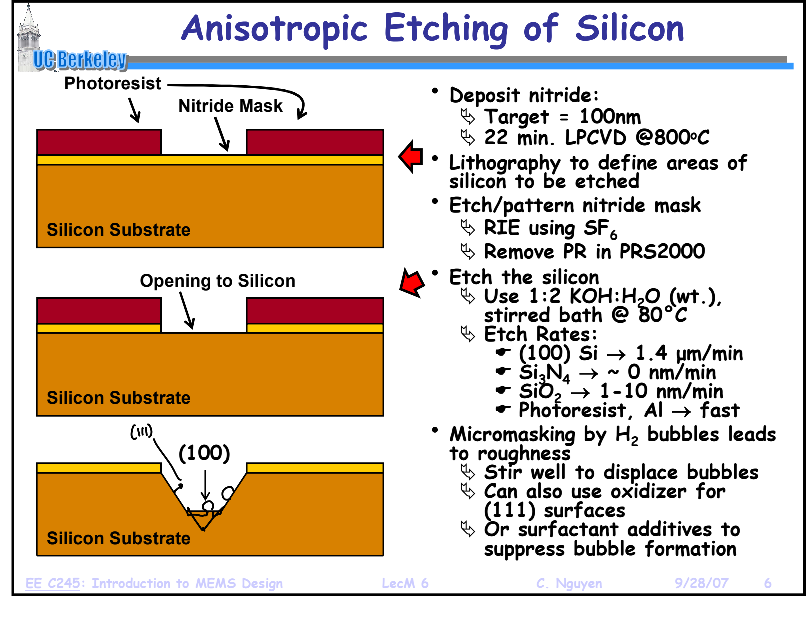

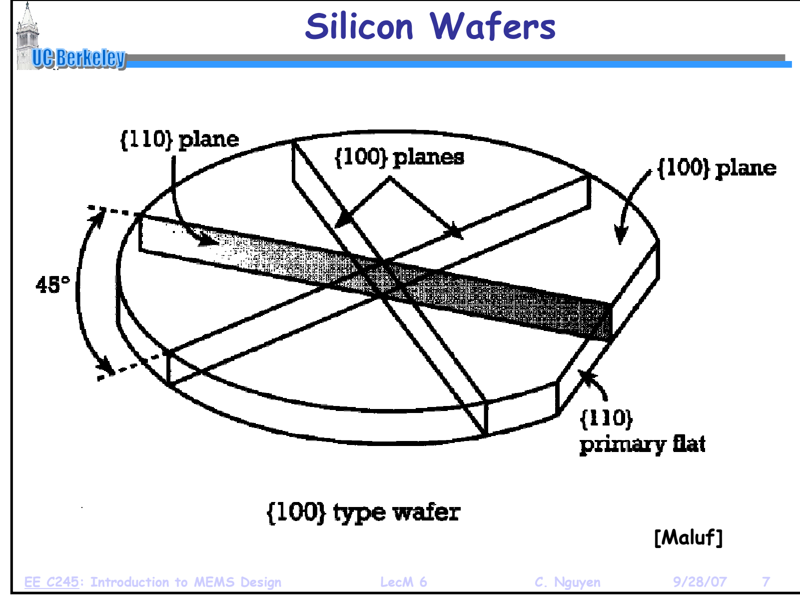

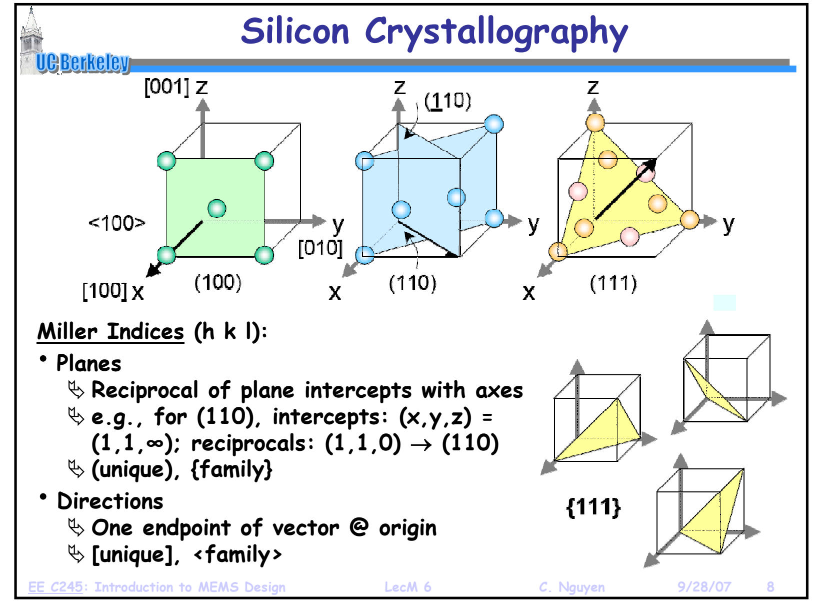

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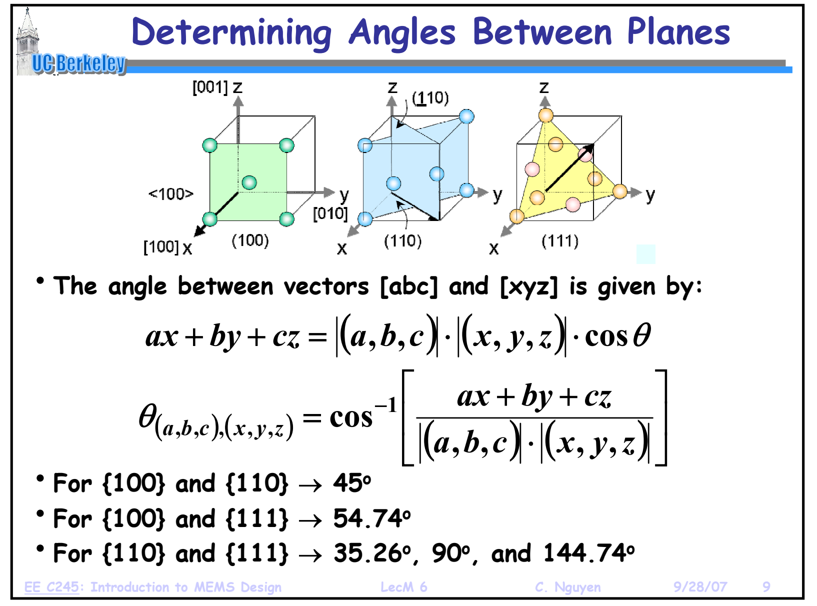

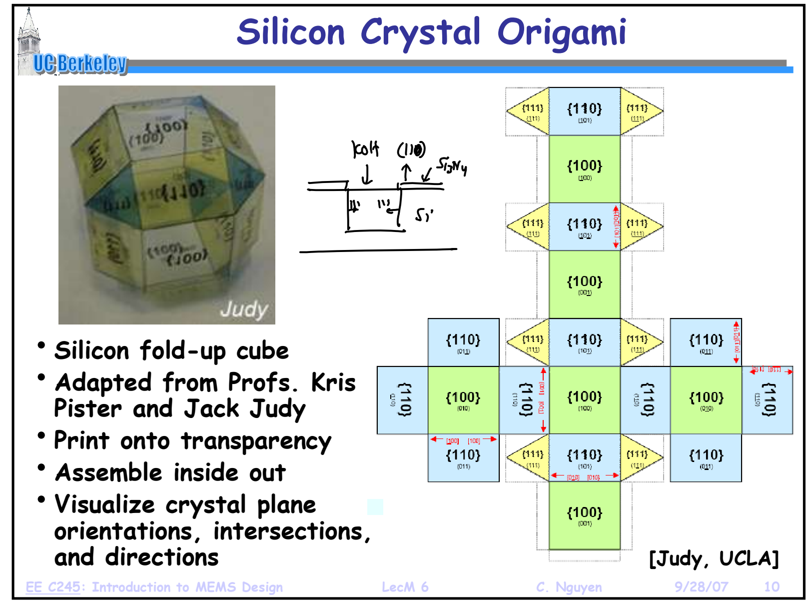

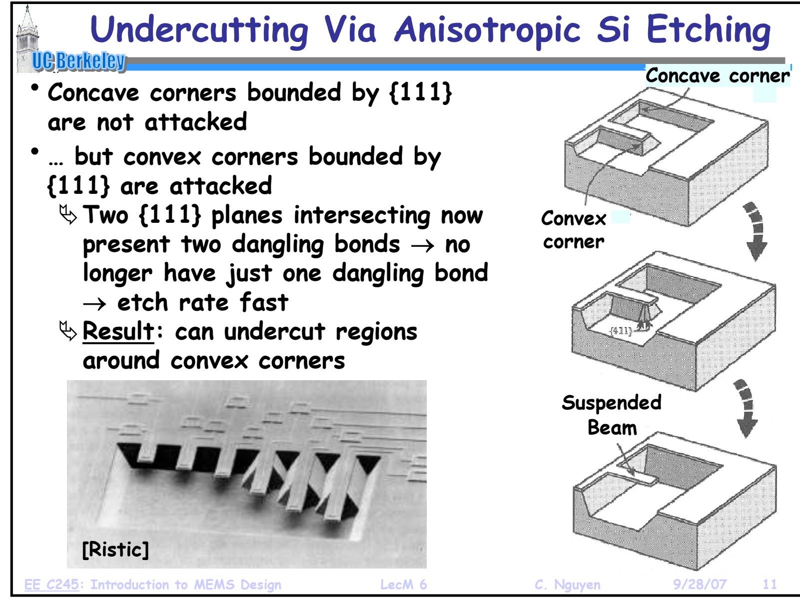

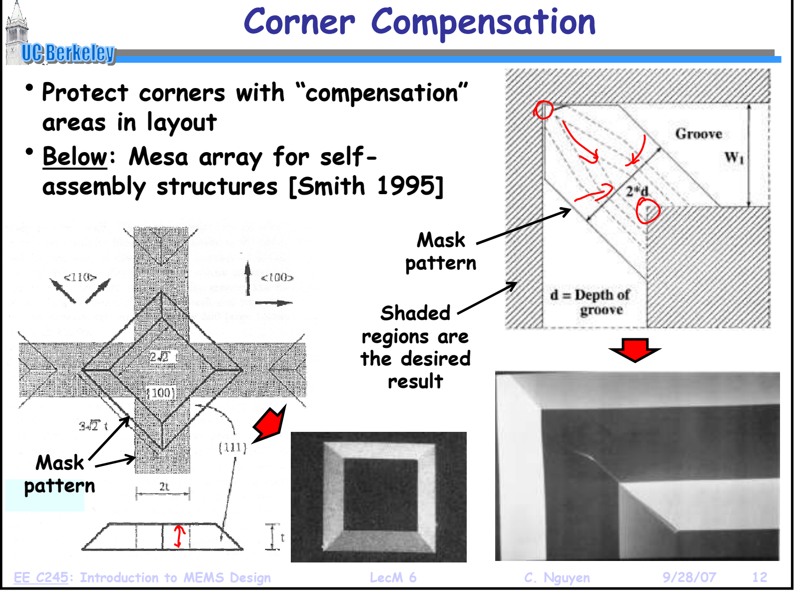

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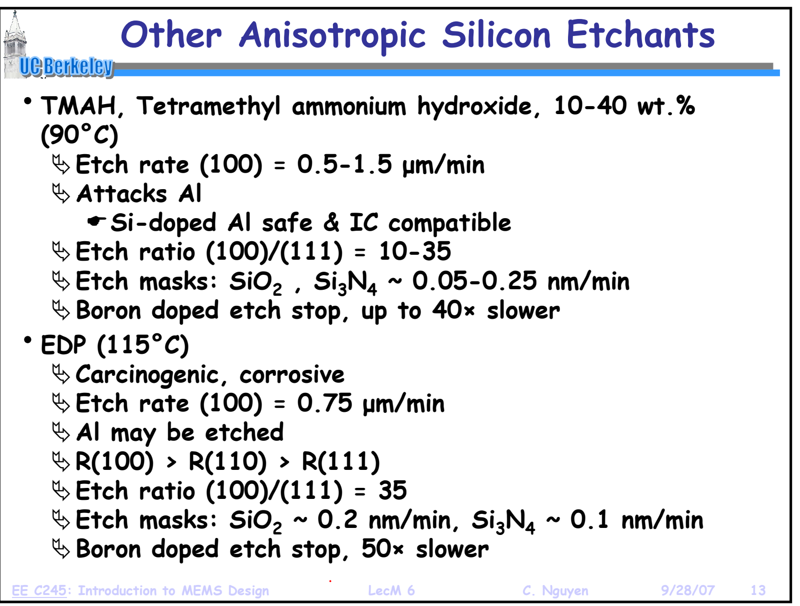

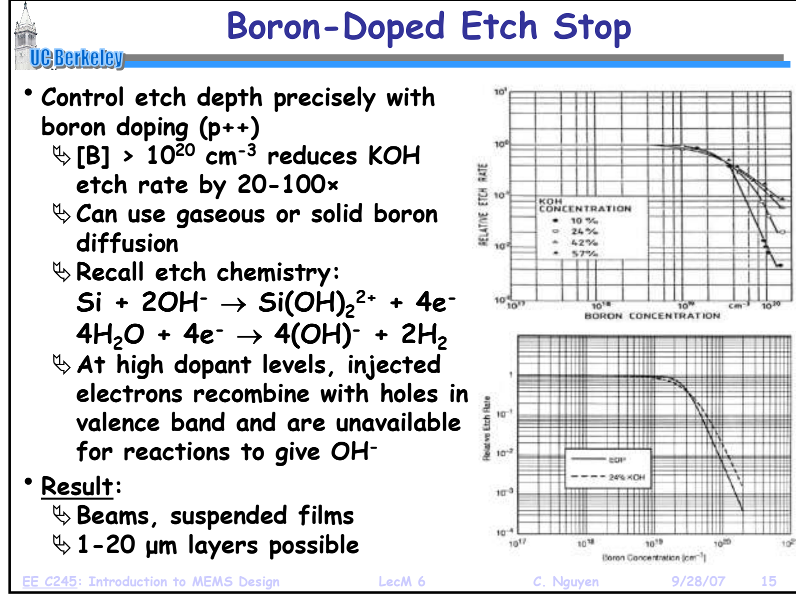

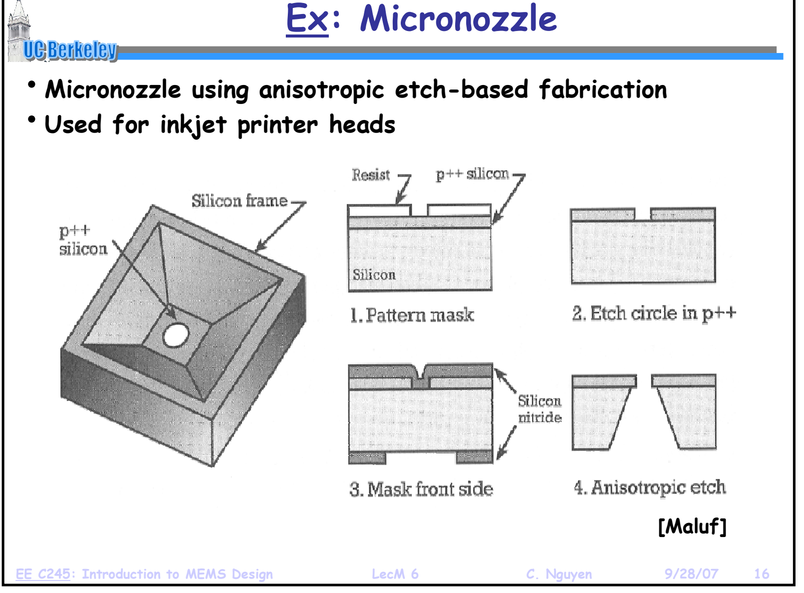

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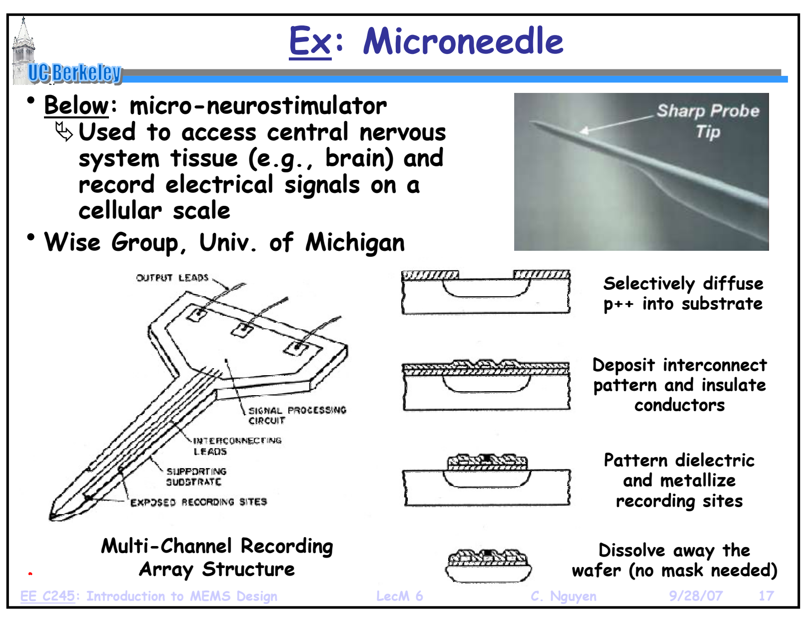

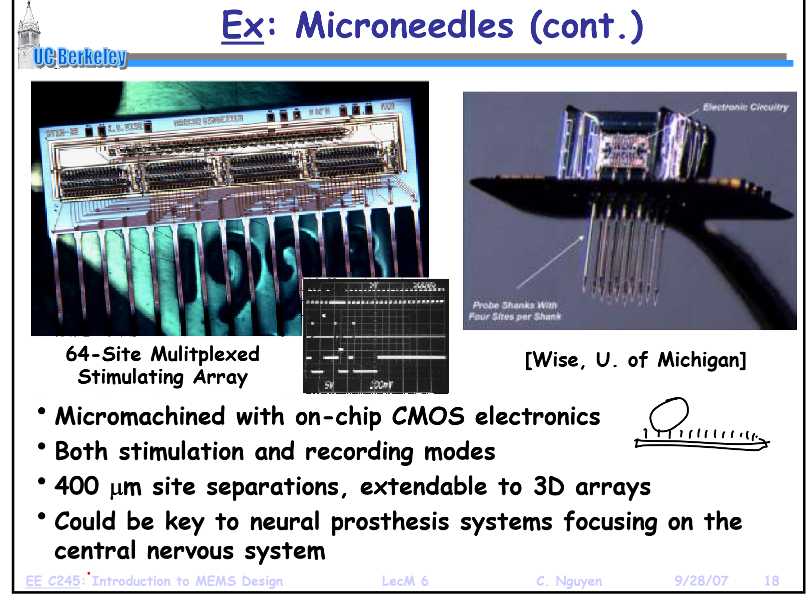

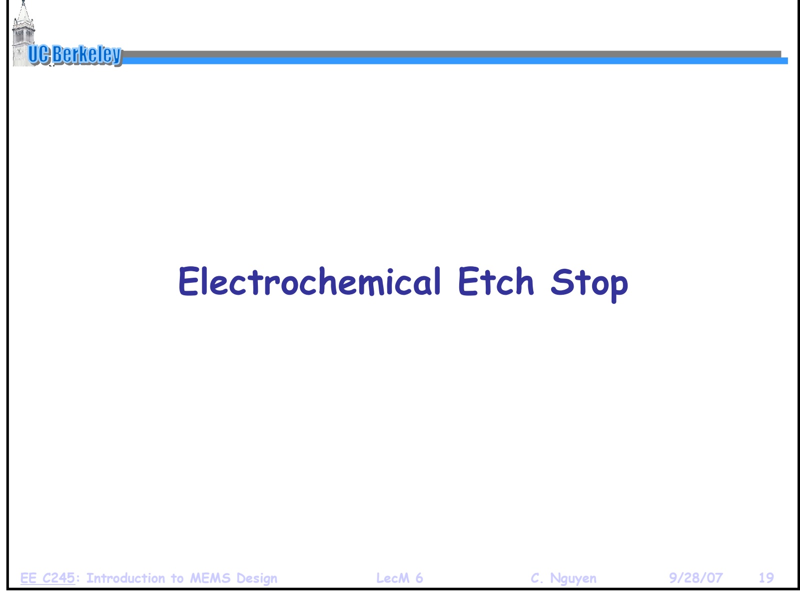

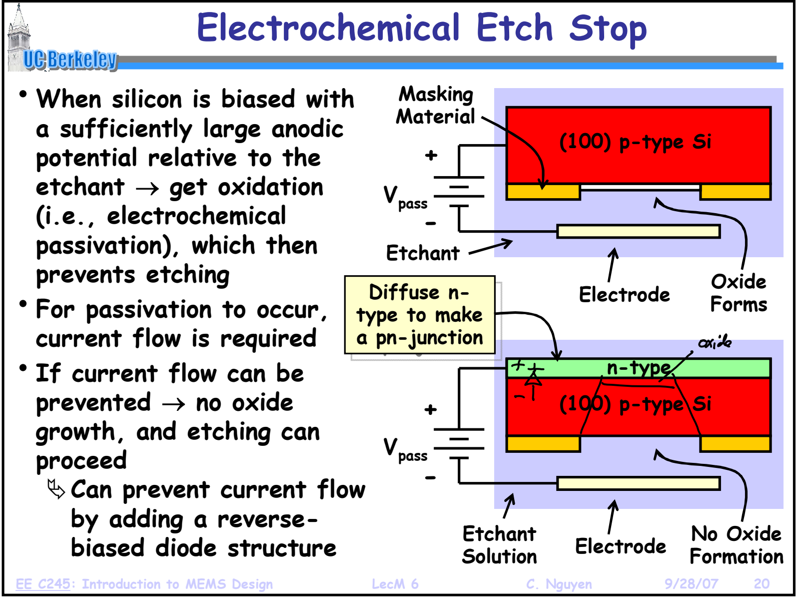

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Electrochemical Etch Stop

- Electrochemical etch stop
  - n-type epitaxial layer grown on p-type wafer forms p-n junction diode
  - $V_p > V_n \rightarrow$ electrical conduction (current flow)
  - $V_p < V_n \rightarrow$ reverse bias current (very little current flow)
- Passivation potential: potential at which thin SiO_2 film forms
  - different for p-Si and n-Si, but basically need the Si to be the anode in an electrolytic setup
- Setup:
  - p-n diode in reverse bias
  - p-substrate floating → etched
  - n-layer above passivation potential → not etched

p-Si, n-Si, OH⁻, electrode, V

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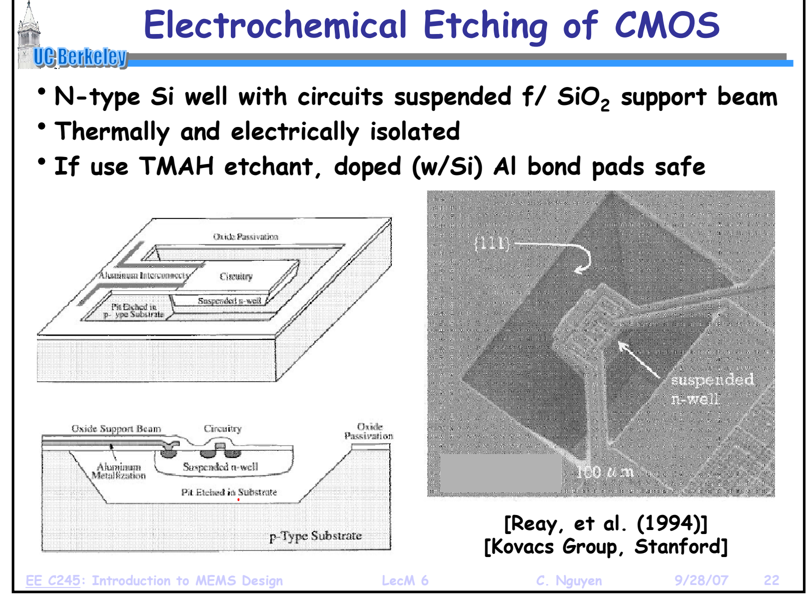
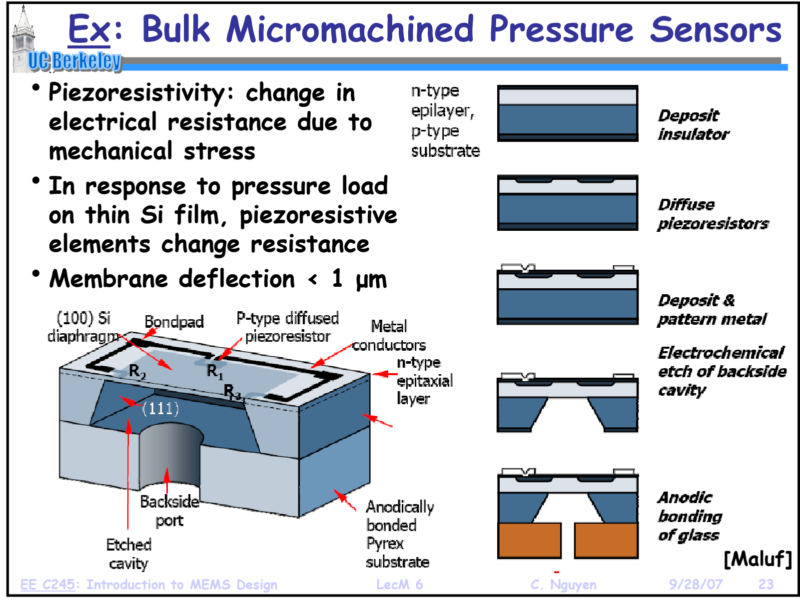
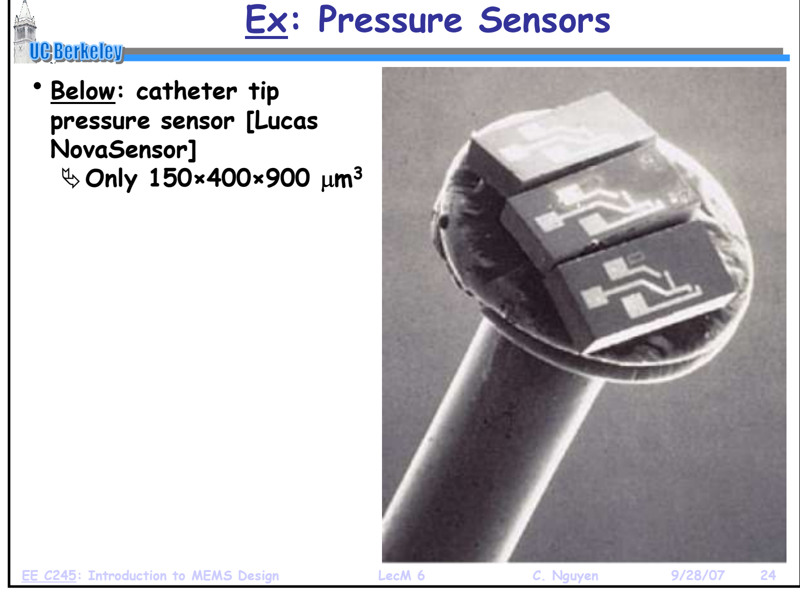




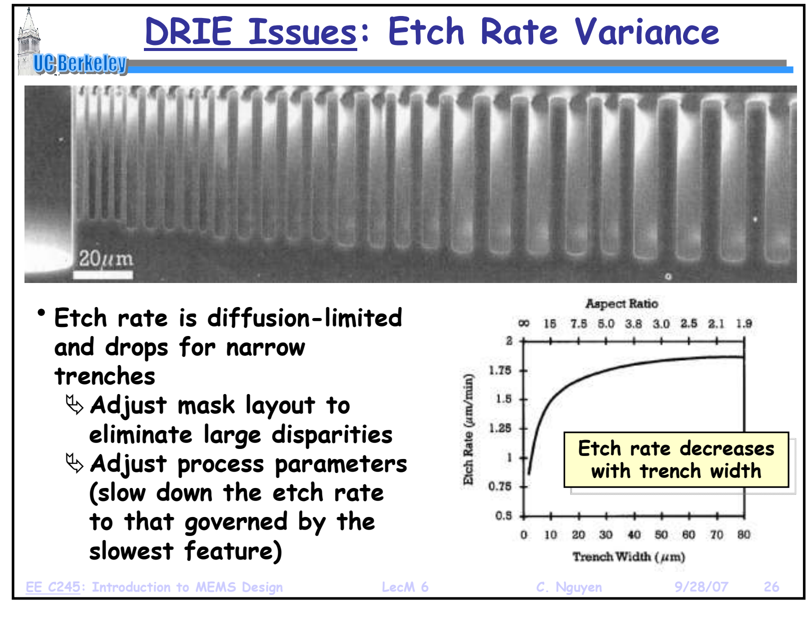


Deep Reactive-Ion Etching (DRIE)

The Bosch process:
- Inductively-coupled plasma
- Etch Rate: 1.5-4 μm/min
- Two main cycles in the etch:
  - Etch cycle (5-15 s): SF_6 (SF_x^+) etches Si
  - Deposition cycle: (5-15 s): C_4F_8 deposits fluorocarbon protective polymer $(CF_2^-)_n$
- Etch mask selectivity:
  - SiO_2 ~ 200:1
  - Photoresist ~ 100:1
- Issue: finite sidewall roughness
  - scalloping < 50 nm
- Sidewall angle: 90° ± 2°

Mask, Silicon, F, SF_x^+, nCF_x^+, Polymer(nCF_2), Maluf

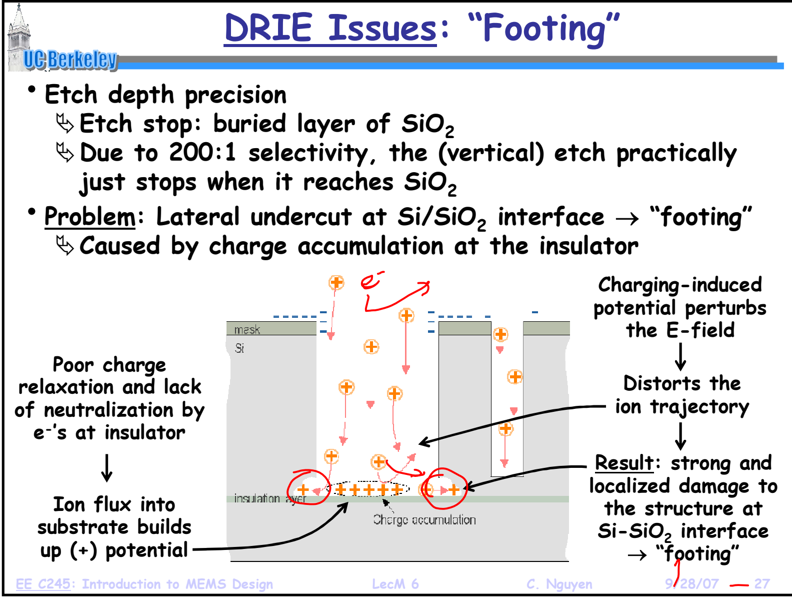
DRIE Issues: Etch Rate Variance



- Etch rate is diffusion-limited and drops for narrow trenches
  - Adjust mask layout to eliminate large disparities
  - Adjust process parameters (slow down the etch rate to that governed by the slowest feature)

DRIE Issues: "Footing"

- Etch depth precision
  - Etch stop: buried layer of SiO_2
  - Due to 200:1 selectivity, the (vertical) etch practically just stops when it reaches SiO_2
- Problem: Lateral undercut at Si/SiO_2 interface → "footing"
  - Caused by charge accumulation at the insulator



Recipe-Based Suppression of "Footing"

- Use higher process pressure to reduce ion charging [Nozawa]
  - High operating pressure → concentration of (-) charge increases and can neutralize (+) surface charge
  - Issue: must introduce as a separate recipe when the etch reaches the Si-insulator interface, so must be able to very accurately predict the time needed for etching
- Adjust etch recipe to reduce overetching [Schmidt]
  - Change C_4F_8 flow rate, pressure, etc., to enhance passivation and reduce overetching
  - Issue: Difficult to simultaneously control footing in a narrow trench and prevent grass in wide trenches
- Use lower frequency plasma to avoid surface charging [Morioka]
  - Low frequency → more ions with low directionality and kinetic energy → neutralizes (-) potential barrier at trench entrance
  - Allows e⁻'s to reach the trench base and neutralize (+) charge → maintain charge balance inside the trench

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Metal Interlayer to Prevent "Footing"

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mask
Si
Metal interlayer (grounded to sub.)
Charge relaxation
Trench for metal definition
glass

Pre-defined metal interlayer grounded to substrate supplies e's to neutralize (+) charge and prevent charge accumulation at the Si-insulator interface

(a) Photolithography 1 (sacrificial)
(b) Preparatory trenches
(c) Metal interlayer deposition
(d) Lift-off (remove PR)
(e) Anodic Bonding
(f) Silicon Thinning
(g) Photolithography 2
(h) DRIE
(i) Remove metal interlayer
(i) Metallize

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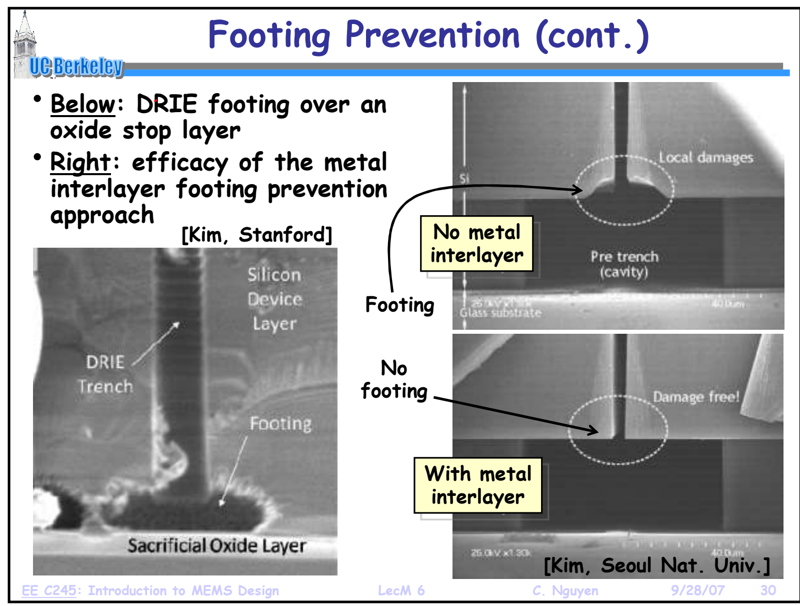

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